Section 2. Forms PTO/SB/08A and 08B (formerly Form PTO-1449)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

Tabrizi, Behna

Serial No:

09/677,291

Date Filed:

Invention:

October 2, 2000

Semiconductor Packaging

Attorney Docket:

1920/107

Art Group Unit:

2812

Examiner Name:

Not Yet Assigned

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT

United States Patents

Examiner Initials	Reference Number	Document Number	Issue Date	Inventor	Class/Subclass
C. C.	AA	4,745,455	05/17/88	Glascock et al.	357/74
C. C.	AB	5,034,044	07/23/91	Glascock	65/42
C.C.	AC	5,133,795	07/28/92	Glascock	65/42
<u>c.c.</u>	AD	5,424,573	06/13/95	Kato et al.	257/431
C.C.	AE	5,610,442	03/11/97	Schneider et al.	257/787
<u>C.C.</u>	AF	5,801,073	09/01/98	Robbins et al.	438/125
<u>C.C.</u>	AG	5,863,812	01/26/99	Manteghi	438/108
<u> </u>	AH	5,877,478	03/02/99	Ando	257/777
<u> </u>	AI	6,013,948	01/11/00	Akram	257/698

Other Documents

Examiner Initials	Reference Number	Author	Title of Article, Title of Journal, Volume Number, Page Numbers, Date
<u> </u>	AJ	Francis et al.	"Stackable 3-D Chip-Scale Package Uses Silicon as the Substrate", Chip Scale Review, vol. 1, No. 1, p.79, May 1997.

AK Savastiouk et "3-D Stacked Wafer-Level Packaging", Advanced al. Packaging Magazine, Cover Story, March 2000.

Examiner Signature: Charsellie lie

Date Considered: Oct. 15, 200/

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation *if not* in conformance and not considered. Include copy of this form with next communication to applicant.

01920/00107 145532.1



SECTION 2:

FORM PTO 1449 - MODIFIED

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Tabrizi, B.

Atty Dkt:

1920/107

Serial No:

09/677,291

Date:

June 20, 2001

Date Filed:

October 2, 2000

Invention:

Seminconductor Packaging

Commissioner for Patents Washington, DC 20231

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

U.S. Documents

Exam. <u>Init.</u>	Ref. <u>No.</u>	Document Number	Issue Date	<u>Name</u>	Class
(,(-	AL	3,436,604	4/1/69	Luecke, et al.	317/101
<i>C.</i> (.	AM	4,936,808	6/26/90	Lee	445/24
C.C.	AN	5,198,963	3/30/93	Gupta, et al.	361/386

Foreign Patent Documents

Exam. <u>Init.</u>	Ref. No.	Document Number	Issue <u>Date</u>	<u>Name</u>
۲.۲.	AO	WO 96/12298	4/25/96	Hsue, et al.
C.C	AP	WO 99/28971	6/10/99	Preuss, et al.

Other Documents

00	AO a	EPO Internationa	I Search Report;	PCT/US	00/27206;	10/2/00
Examir	ner: / ////2	EPO Internationa			,	

Date Considered: Oct. 15, 200/

NOTE FOR EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance AND not considered. Include copy of this form with next communication to applicant.

01920/00108 160652.1